

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of

AOKI et al

Atty. Ref.: 4074-7

Serial No. to be assigned

Group:

Filed: October 22, 2003

Examiner:

For: PHOTOMASK DEFECT TESTING METHOD, PHOTOMASK
MANUFACTURING METHOD AND SEMICONDUCTOR INTEGRATED
CIRCUIT MANUFACTURING METHOD

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October 22, 2003

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

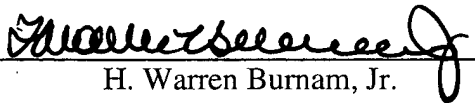
INFORMATION DISCLOSURE STATEMENT

As suggested by 37 C.F.R. 1.97, the undersigned attorney brings to the attention of the Patent and Trademark Office the references listed on the attached form PTO-1449, a copy of each of which is enclosed. This is not to be construed as a representation that a search has been made or that no better prior art exists, or that a reference is relevant merely because cited.

The Examiner is requested to initial the attached form PTO-1449 and to return a copy of the initialed document to the undersigned as an indication that the attached references have been considered and made of record.

Respectfully submitted,

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